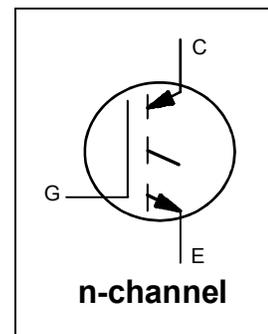


**INSULATED GATE BIPOLAR TRANSISTOR**

$V_{CES} = 600V$ $I_C = 30A, T_C = 100^\circ C$ $T_{J(max)} = 175^\circ C$ $V_{CE(on)} \text{ typ} = 1.65V @ I_C = 18A$
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**Applications**

- Industrial Motor Drives
- Inverter
- UPS
- Welding

<b>G</b>	<b>C</b>	<b>E</b>
Gate	Collector	Emitter

Features	Benefits
Low $V_{CE(ON)}$ and switching losses	High efficiency in a wide range of applications and switching frequencies
Square RBSOA and maximum junction temperature 175°C	Improved reliability due to rugged hard switching performance and higher power capability
Positive $V_{CE(ON)}$ temperature coefficient	Excellent current sharing in parallel operation
5µs short circuit SOA	Enables short circuit protection scheme
Lead-free, RoHS compliant	Environmentally friendly

Base part number	Package Type	Standard Pack		Orderable part number
		Form	Quantity	
IRGC4630B	Wafer	Wafer	1	IRGC4630B

**Mechanical Parameters**

Die Size	3.302 x 3.302	mm <sup>2</sup>
Minimum Street Width	75	µm
Emitter Pad Size (Included Gate Pad)	See Die Drawing	mm <sup>2</sup>
Gate Pad Size	0.5 x 0.6	
Area Total / Active	10.9 / 6.4	
Thickness	70	µm
Wafer Size	150	mm
Notch Position	0	Degrees
Maximum-Possible Chips per Wafer	1408pcs.	
Passivation Front side	Silicon Nitride	
Front Metal	Al, Si (4µm)	
Backside Metal	Al (1kA°), Ti (1kA°), Ni (4kA°), Ag (6kA°)	
Die Bond	Electrically conductive epoxy or solder	
Reject Ink Dot Size	0.25 mm diameter minimum	

**Maximum Ratings**

	Parameter	Max.	Units
$V_{CE}$	Collector-Emitter Voltage, $T_J=25^\circ\text{C}$	600	V
$I_C$	DC Collector Current	①	A
$I_{LM}$	Clamped Inductive Load Current ④	72	A
$V_{GE}$	Gate Emitter Voltage	$\pm 20$	V
$T_J, T_{STG}$	Operating Junction and Storage Temperature	-40 to +175	$^\circ\text{C}$

**Static Characteristics (Tested on wafers) .  $T_J=25^\circ\text{C}$** 

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)CES}$	Collector-to-Emitter Breakdown Voltage	600	—	—	V	$V_{GE} = 0\text{V}, I_C = 100\mu\text{A}$ ⑤
$V_{CE(sat)}$	Collector-to-Emitter Saturated Voltage	—	1.1	1.325		$V_{GE} = 15\text{V}, I_C = 5\text{A}, T_J = 25^\circ\text{C}$
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	4.0	—	6.5		$I_C = 500\mu\text{A}, V_{GE} = V_{CE}$
$I_{CES}$	Zero Gate Voltage Collector Current	—	2.0	25	$\mu\text{A}$	$V_{CE} = 600\text{V}, V_{GE} = 0\text{V}$
$I_{GES}$	Gate Emitter Leakage Current	—	—	$\pm 100$	nA	$V_{CE} = 0\text{V}, V_{GE} = \pm 20\text{V}$

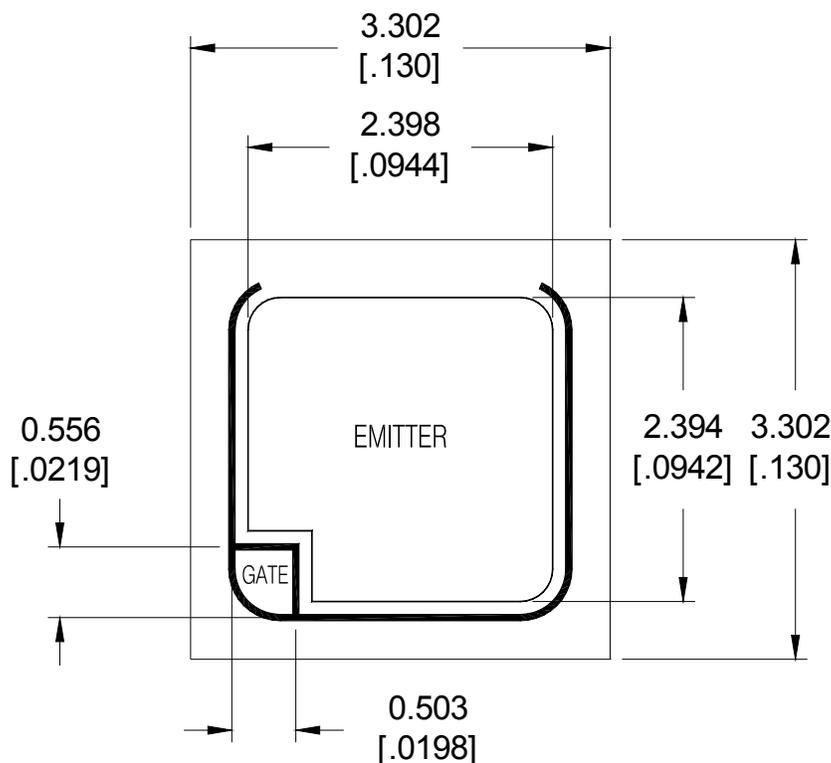
**Electrical Characteristics (Not subject to production test- Verified by design/characterization)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{CE(sat)}$	Collector-to-Emitter Saturated Voltage	—	1.65	1.95	V	$V_{GE} = 15\text{V}, I_C = 18\text{A}, T_J = 25^\circ\text{C}$
		—	2.15	—		$V_{GE} = 15\text{V}, I_C = 18\text{A}, T_J = 175^\circ\text{C}$
SCSOA	Short Circuit Safe Operating Area	5	—	—	$\mu\text{s}$	$V_{GE}=15\text{V}, V_{CC}=400\text{V},$ ② $R_G=22\Omega, V_P \leq 600\text{V}, T_J=150^\circ\text{C}$
RBSOA	Reverse Bias Safe Operating Area	FULL SQUARE				$T_J = 175^\circ\text{C}, I_C = 72\text{A}$ $V_{CC} = 480\text{V}, V_P \leq 600\text{V}$ $R_g = 22\Omega, V_{GE} = +20\text{V to } 0\text{V}$
$C_{ISS}$	Input Capacitance	—	1043	—	pF	$V_{GE} = 0\text{V}$
$C_{OSS}$	Output Capacitance	—	87	—		$V_{CE} = 30\text{V}$
$C_{RSS}$	Reverse Transfer Capacitance	—	32	—		$f = 1.0\text{MHz}$
$Q_g$	Total Gate Charge (turn-on)	—	35	—	nC	$I_C = 18\text{A}$ ⑥
$Q_{ge}$	Gate-to-Emitter Charge (turn-on)	—	10	—		$V_{GE} = 15\text{V}$
$Q_{gc}$	Gate-to-Collector Charge (turn-on)	—	15	—		$V_{CC} = 400\text{V}$

**Switching Characteristics (Inductive Load-Not subject to production test-Verified by design/characterization)**

	Parameter	Min.	Typ.	Max.	Units	Conditions ③
$t_{d(on)}$	Turn-On delay time	—	40	—	ns	$I_C = 18\text{A}, V_{CC} = 400\text{V}$ $R_G = 22\Omega, V_{GE}=15\text{V}, L=200\mu\text{H}$ $T_J = 25^\circ\text{C}$
$t_r$	Rise time	—	25	—		
$t_{d(off)}$	Turn-Off delay time	—	105	—		
$t_f$	Fall time	—	25	—		
$t_{d(on)}$	Turn-On delay time	—	40	—		$I_C = 18\text{A}, V_{CC} = 400\text{V}$ $R_G = 22\Omega, V_{GE}=15\text{V}, L= 200\mu\text{H}$ $T_J = 175^\circ\text{C}$
$t_r$	Rise time	—	25	—		
$t_{d(off)}$	Turn-Off delay time	—	120	—		
$t_f$	Fall time	—	40	—		

# Die Drawing


**NOTES:**

1. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
2. CONTROLLING DIMENSION: [INCH].
3. LETTER DESIGNATION:  
 S = SOURCE    SK = SOURCE KELVIN    E = EMITTER  
 G = GATE      IS = CURRENTSENSE
4. DIMENSIONAL TOLERANCES:  
 BONDING PADS: < 0.635 TOLERANCE = +/- 0.013  
 WIDTH < [.0250] TOLERANCE = +/- [.0005]  
 & > 0.635 TOLERANCE = +/- 0.025  
 LENGTH > [.0250] TOLERANCE = +/- [.0010]  
 OVERALL DIE: < 1.270 TOLERANCE = +/- 0.102  
 WIDTH < [.050] TOLERANCE = +/- [.004]  
 & > 1.270 TOLERANCE = +/- 0.203  
 LENGTH > [.050] TOLERANCE = +/- [.008]
5. DIE THICKNESS = 0.070 [.0028] TOL: = 0.007 [.0003]

**Notes:**

- ① The current in the application is limited by  $T_{JMax}$  and the thermal properties of the assembly.
- ② Not subject to production test- Verified by design / characterization.
- ③ Values influenced by parasitic L and C in measurement.
- ④  $V_{CC} = 80\% (V_{CES})$ ,  $V_{GE} = 20V$ ,  $L = 200\mu H$ ,  $R_G = 22\Omega$ .
- ⑤ Refer to AN-1086 for guidelines for measuring  $V_{(BR)CES}$  safely
- ⑥ Die Level Characterization.

### Additional Testing and Screening

For Customers requiring product supplied as Known Good Die (KGD) or requiring specific die level testing, please contact your local IR Sales.

### Shipping

Sawn Wafer on Film. Please contact your local IR sales office for non– standard shipping options

### Handling

- Product must be handled only at ESD safe workstations. Standard ESD precautions and safe work environments are as defined in MIL-HDBK-263.
- Product must be handled only in a class 10,000 or better-designated clean room environment.
- Singulated die are not to be handled with tweezers. A vacuum wand with a non-metallic ESD protected tip should be used.

### Wafer/Die Storage

- Proper storage conditions are necessary to prevent product contamination and/or degradation after shipment.
- Note: To reduce the risk of contamination or degradation, it is recommended that product not being used in the assembly process be returned to their original containers and resealed with a vacuum seal process.
- Sawn wafers on a film frame are intended for immediate use and have a limited shelf life.

### Further Information

For further information please contact your local IR Sales office or email your enquiry to <http://die.irf.com>

Data and specifications subject to change without notice.  
This product has been designed and qualified for Industrial market.  
Qualification Standards can be found on IR's Web site.

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**IOR** Rectifier

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